

<b>Search Notes</b> 				<b>Application/Control No.</b> 10/618,790 <b>Examiner</b> Anthony Weier	<b>Applicant(s)/Patent under Reexamination</b> DIBBS, RICHARD J. <b>Art Unit</b> 1761	
<b>SEARCHED</b>				<b>SEARCH NOTES (INCLUDING SEARCH STRATEGY)</b>		
Class	Subclass	Date	Examiner		DATE	EXMR
updated	previous search	7/7/2006	AW			
<b>INTERFERENCE SEARCHED</b>						
Class	Subclass	Date	Examiner			